

Figures

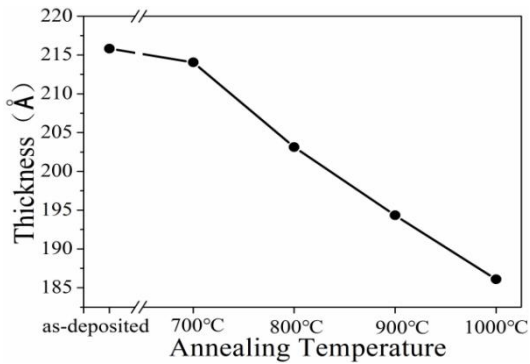


Figure 1. Thickness of AlN films with different annealing temperature for 1 min in N₂ atmosphere.

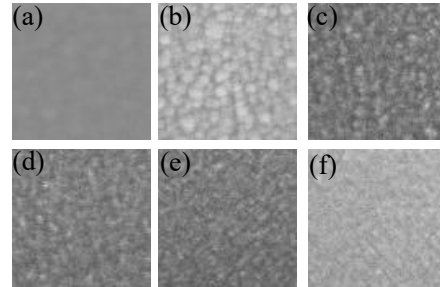


Figure 2. SEM images of (a) Si substrate, (b) as-deposited AlN film and after annealing at (c) 700°C, (d) 800°C, (e) 900°C and (f) 1000°C.

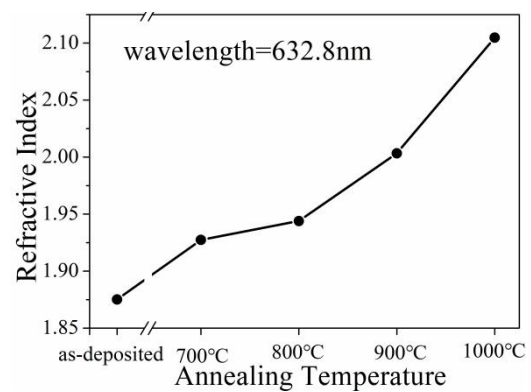
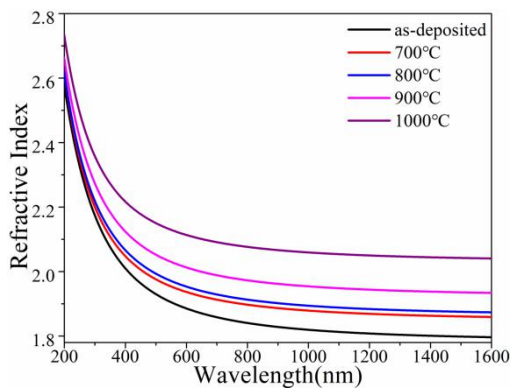


Figure 3. (a) Evolution of the refractive index of AlN films with different annealing temperature. (b) the refractive index of AlN films at a wavelength of 632.8 nm.

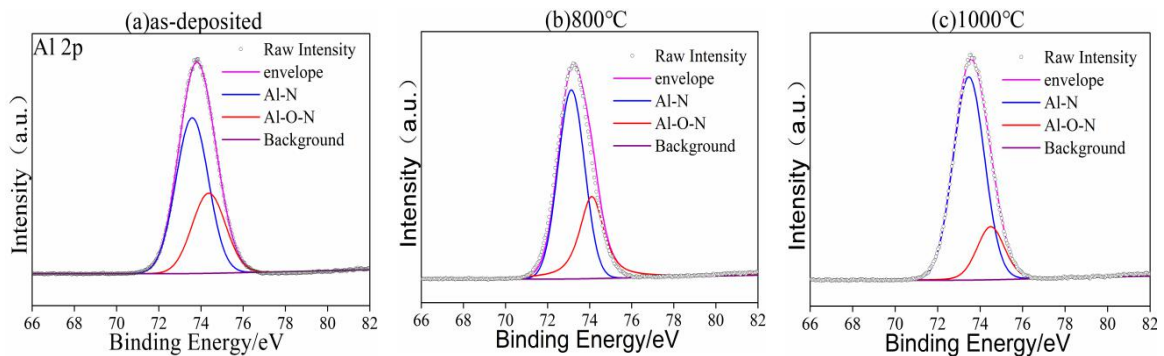


Figure 4. XPS spectra of Al 2p in AlN films: (a) as-deposited, (b) annealed at 800°C and (c) annealed at 1000°C.